

Application/Control No.	Applicant(s)/Patent under Reexamination
09/923,242	HUSTH, ARNE
Examiner	Art Unit
Ted M. Wang	2611

SEARCHED						
Class	Subclass	Date	Examiner			
	UPDATED					
375	319, 324	4/22/2008	TW			
375	340, 350	4/22/2008	TW			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
375	319, 324	4/22/2008	TW		
375	340, 350	4/22/2008	TW		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	4/22/2008	TW		
leeexplor - Author - Husth Arne	4/22/2008	TW		
IEEExplor - Advance - modulation and (extreme* or maximum or minimum) and DC (compensat* or offset)	4/22/2008	TW		
ODP- searched and reviewed from PALM and EAST	4/22/2008	TW		